[Workshop WMA]

Building the World's Fastest 8-bit ADC - In CMOS

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Outline

- Trends in CMOS ADCs
- Massively Interleaved ADCs
 - 4 GSa/s
 - 20 GSa/s



ADC Dynamic Range vs. Input BW - ISSCC 1998-2005



ADC Figure of Merit vs. Input BW - ISSCC 1998-2005 FOM = P / ($2^{ENOB} * 2 * F_{IN}$)





Some Trends in CMOS ADCs

- Increasing focus on power reduction
 - Battery-powered (e.g., toys, laptops) supply limited
 - High-end ADCs (e.g., scopes) dissipation limited
 - System-on-a-Chip (e.g., wireless, PDAs) can have both limits
- Increasing numbers of embedded ADCs and DACs
- Lower-voltage CMOS tends to take *more* power to maintain the same SNR

Increased advantage in replacing analog functions with digital

- Lower-voltage CMOS makes precision analog circuits harder
 - Increasing use of simpler analog circuits
 - Increasing use of digital techniques to address analog imperfections
- Calibration Techniques
 - Foreground calibration used in some ADCs
 - Background calibration starting to move beyond academic ADCs

Process Selection

Poulton's Polemic:

"Don't use III-V FETs if HBTs will work. Don't use III-V HBTs if silicon will work. Don't use bipolar if CMOS will work."

Robertson's Reason:

"If we don't do it in CMOS, someone else will."

- CMOS is cheaper (at least in volume)
- CMOS circuits are more widely reusable
- CMOS designers are less difficult to hire
- But some jobs do need other technologies

What's in a Scope?



- Resolution 8 bits
- Realtime BW up to F_S/2.5
- Money specs: bandwidth and sample rate

Designing Scope ADCs the Old Way

- Approach:
 - Use the fastest technology available
 - Design for the highest sample rate
 - If necessary, time-interleave 2-6x
- State of the Art in 1996:
 - 25-GHz bipolar process
 - 2-GSa/s unit ADC
 - Interleaved 2x to get 4 GSa/s on one chip
 - 2.2 GHz BW (with 4x interleave)
 - 6.5 effective bits at 100 MHz
 - 5.4 effective bits at 1 GHz
 - 13 watts
 - Expensive



Custom thick-film package with custom bipolar ADC chip and custom CMOS memory chip



Could We Use CMOS for Scope ADCs?

"Don't be stupid:"

- CMOS ADCs are 60 times too slow (in 1996)
- CMOS transistors are 10 times less accurate than bipolars

"But..."

- CMOS chips are cheap and transistors are virtually free
- Could integrate with memory
- Might be lower power
- One high-BW circuit: the NMOS track-and-hold (T/H)



Idea: Massive Interleaving of Low-Power ADCs

- Start with the most power-efficient CMOS ADC slice
- Time-interleave like crazy to get sample rate
- Fix up analog accuracy through calibration

Challenges:

Track/Hold : Bandwidth, Channel mismatch, Clocks ADC: Sample Rate, Power/sample, Circuit area



CMOS ADC Chip Architecture (4 GSa/s)



- 32 time-interleaved pipeline ADCs at 125 MSa/s
- Net sample rate is 4 GSa/s

Timing Error and ADC Resolution



 Fast signal converts a sample timing error (dT) to an apparent voltage error (dV).



Rule of thumb: 1 ps / 1 GHz --> 7 effective bits

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Timing Error Signature



Larger voltage errors during high dV/dt. Fs = 20 GSa/s Fin = 5007.5 MHz 5.0 effective bits



- Max input edge to sampling edge delay: 2 ns
 - ~ 1 ps jitter < 1 ps static error after cal

Simplified Input Track/Hold



To achieve highest bandwidth and linearity:

- ONLY 1 NMOS FET in signal path
- Restrict C_{hold} to only T/H and load parasitics
- Low common mode input voltage
- Low-swing differential signal (250 mV peak)
- Fastest possible full-swing clock edge

In 0.35 um: 2 GHz bandwidth, -50 dB HD3 In 0.18 um: 7 GHz bandwidth, -50 dB HD3



Analog Front End Implementation



- Parasitic-only hold capacitance (140 fF)
- Only 1 ns (12.5%) pulse width for Clk_s
- Reset phase
- Transconductor (V/I) current output drives ADC



Only 1 comparator per stage

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Current-Mode T/H and Gain



- Good Linearity: Current mirrors with cascodes are 8 bit linear.
- Poor Accuracy: Gain and offset errors

Radix Converter Principle

- ADC is performing linear operations.
- Output bits are can be linearly combined to represent input signal:

ADC output = $b_{11}.w_{11} + b_{10}.w_{10} + \dots + b_1.w_1 + b_0.w_0$

- Traditional design: Accurate analog design
 - w_i are powers of 2
 - No explicit Multiply/Accumulate needed.
- Digital Calibration: Approximate analog design.
 - Actual w_i are measured through calibration
 - Compliments reduced radix approach.
 - Requires Multiply/Accumulate block.

Multiply/Accumulate (Radix Converter)

Calculate and download bit weights during cal.



- 1 bit "Multiply" is just a memory access
- Look-up table is an alternative.

What Needs To Be Calibrated?



Offline Calibration with DC and Pulse sources

Advantages of a Calibration Approach

- We can get away with approximate analog design.
 - No 6-sigma 1% matching needed in ADC slice.
 - Do not need precise modelling of 2nd order mismatch effects (like layout related delta W).
 - Time delay mismatch can be tolerated.
 - Signal path offset and gain errors are easily cal'ed.
 - If an effect can be calibrated, and a reasonable bound on its effect computed, then design of the calibration DAC is relatively simple.
- Benefits:
 - Reduced design time.
 - High yield possible with many ADCs / chip.



4 GSa/sec ADC Chip Layout



7.1 mm x 4.0 mm 300,000 FETs 4.6 W 0.35 μ m



Acquisition Before Calibration







ADC Effective Bits vs Input Frequency



0.18 μm CMOS: 20 GSa/s, 6 GHz



- 2x faster process, 5x higher sample rate, 6x higher BW
- 80 ADC slices, larger C_{in} --> SiGe input buffer chip
- 160 Gb/s data rate --> 1 MB on-board sample memory

20 GSa/sec ADC Module



40 GHz SiGe 1 x 2 mm 1000 transistors

0.18-um CMOS 14 x 14 mm 50M transistors

Package: 438-ball BGA 35 x 35 mm

System Challenges: Low Voltage + Supply Droop **Digital Complexity**



ADC Effective Bits vs Input Frequency



6.5 effbits at low frequency. 0.7 ps rms jitter

ADC Chips - Key Specs

	4 GSa/s	20 GSa/s	Units
Nominal Sample Rate	4	20	GSa/s
Resolution	8	8	bits
3 dB Bandwidth	1.6	6.6	GHz
Accuracy @ 30 MHz	7.0	6.5	effective bits
Fs/4	6.2	5.0	(ENOB)
Timing Error (jitter)	1.2	0.7	ps rms
Noise	0.6	0.9	LSB rms
INL / DNL	±0.3 / ±0.2	±0.4 / ±0.3	LSB
Power	4.6	10	Watts
IC Technology	0.35 µm	0.18µm / 35GHz	CMOS / SiGe
Chip Size	7.14 x 4.04	14x14 / 1x2	mm ²
Transistors	300k	50M / 1k	
Package	27 mm	35 mm	BGA
Memory	0	1 M	samples

Monolithic ADCs in 2004



ENOB at Fs/4

Energy per Sample



■ Twice the sample rate at 1/3 the power of the nearest competitor

Conclusions

- Trends
 - Increasing importance of power efficiency and low cost
 - CMOS is taking over ever more of the ADC market
- Interleaved ADCs
 - Massive time-interleaving allows CMOS to compete at the highest sample rates
 - Very high BW possible with NMOS T/H
 - Calibration is a key to utilizing low-power, inaccurate circuits
 - The world's fastest 8-bit ADC is now CMOS



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